	Reference Specification
	ard Certified Metal Terminal Type Multilayer Ceramic Capacitors for e (Powertrain/Safety) /Type MF [X1/Y2:250Vac, X1/Y2:1000Vdc]
Droduct opcificati	ions in this sateled are so of Esh. 2025, and are subject to shange or
obsolescence with	ions in this catalog are as of Feb. 2025, and are subject to change or nout notice. a approval sheet before ordering.Please read rating and Cautions first.

### Storage and Operation Conditions

- 1. The performance of chip monolithic ceramic capacitors may be affected by the storage conditions.
  - 1-1. Store the capacitors in the following conditions:Room Temperature of +5°C to +40°C and a Relative Humidity of 20% to 70%.
    - (1) Sunlight, dust, rapid temperature changes, corrosive gas atmosphere, or high temperature and humidity conditions during storage may affect solderability and packaging performance. Therefore, please maintain the storage temperature and humidity. Use the product within six months after delivery, as prolonged storage may cause oxidation of the electrodes.
    - (2) Please confirm solderability before using after six months. Store the capacitors without opening the original bag. Even if the storage period is short, do not exceed the specified atmospheric conditions.
  - 1-2. Corrosive gas can react with the termination(external) electrodes or lead wires of capacitors, and result in poor solderability. Do not store the capacitors in an atmosphere consisting of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas, etc.).
  - 1-3. Due to moisture condensation caused by rapid humidity changes, or the photochemical change caused by direct sunlight on the terminal electrodes and/or the resin/epoxy coatings, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or in high humidity conditions.

### Rating

### 1. Temperature Dependent Characteristics

- 1. The electrical characteristics of a capacitor can change with temperature.
  - 1-1. For capacitors having larger temperature dependency, the capacitance may change with temperature changes. The following actions are recommended in order to ensure suitable capacitance values.
    - (1) Select a suitable capacitance for the operating temperature range.
    - (2) The capacitance may change within the rated temperature. When you use a high dielectric constant type capacitor in a circuit that needs a tight (narrow) capacitance tolerance (e.g., a time-constant circuit), please carefully consider the temperature characteristics, and carefully confirm the various characteristics in actual use conditions and the actual system.

## 2. Measurement of Capacitance

- 1. Measure capacitance with the voltage and frequency specified in the product specifications.
  - 1-1. The output voltage of the measuring equipment may decrease occasionally when capacitance is high. Please confirm whether a prescribed measured voltage is impressed to the capacitor.
- 1-2. The capacitance values of high dielectric constant type capacitors change depending on the AC voltage applied. Please consider the AC voltage characteristics when selecting a capacitor to be used in an AC circuit.

### 3. Applied Voltage

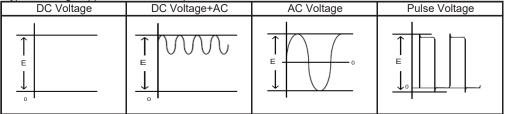
 Do not apply a voltage to a safety standard certified product that exceeds the rated voltage as called out in the specifications. Applied voltage between the terminals of a safety standard certified product shall be less than or equal to the rated voltage (+ 10%). When a safety standard certified product is used as a DC voltage product, the AC rated voltage value becomes the DC rated voltage value.

(Example:AC250V (r.m.s.) rated product can be used as DC250V (+ 10%) rated product.)

- If both AC rated voltage and DC rated voltage are specified, apply the voltage lower than the respective rated voltage. 1-1. When a safety standard certified product is used in a circuit connected to a commercial power supply,
- ensure that the applied commercial power supply voltage including fluctuation should be less than 10% above its rated voltage.
- 1-2. When using a safety standard certified product as a DC rated product in circuits other than those connected to a commercial power supply.

When AC voltage is superimposed on DC voltage, the zero-to-peak voltage shall not exceed the rated DC voltage. When AC voltage or pulse voltage is applied, the peak-to-peak voltage shall not exceed the rated DC voltage.

## Typical Voltage Applied to the DC Capacitor



(E: Maximum possible applied voltage.)

2. Abnormal voltages (surge voltage, static electricity, pulse voltage, etc.) shall not exceed the rated DC voltage.

### 4. Type of Applied Voltage and Self-heating Temperature

1. Confirm the operating conditions to make sure that no large current is flowing into the capacitor due to the continuous application of an AC voltage or pulse voltage. When a DC rated voltage product is used in an AC voltage circuit or a pulse voltage circuit, the AC current or pulse current will flow into the capacitor; therefore check the self-heating condition. Please confirm the surface temperature of the capacitor so that the temperature remains within the upper limits of the operating temperature, including the rise in temperature due to self-heating. When the capacitor is used with a high-frequency voltage or pulse voltage, heat may be generated by dielectric loss.

### 5. DC Voltage and AC Voltage Characteristics

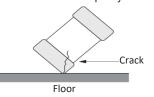
- 1. The capacitance value of a high dielectric constant type capacitor changes depending on the DC voltage applied. Please consider the DC voltage characteristics when a capacitor is selected for use in a DC circuit.
  - 1-1. The capacitance of ceramic capacitors may change sharply depending on the applied voltage (see figure). Please confirm the following in order to secure the capacitance.
    - (1) Determine whether the capacitance change caused by the applied voltage is within the allowed range.
    - (2) In the DC voltage characteristics, the rate of capacitance change becomes larger as voltage increases, even if the applied voltage is below the rated voltage. When a high dielectric constant type capacitor is used in a circuit that requires a tight (narrow) capacitance tolerance (e.g., a time constant circuit), please carefully consider the voltage characteristics, and confirm the various characteristics in actual operating conditions in an actual system.
- 2. The capacitance values of high dielectric constant type capacitors changes depending on the AC voltage applied. Please consider the AC voltage characteristics when selecting a capacitor to be used in an AC circuit.

### 6. Capacitance Aging

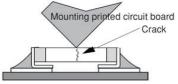
1. The high dielectric constant type capacitors have the characteristic in which the capacitance value decreases with the passage of time. When you use high dielectric constant type capacitors in a circuit that needs a tight (narrow) capacitance tolerance (e.g., a time-constant circuit), please carefully consider the characteristics of these capacitors, such as their aging, voltage, and temperature characteristics. In addition, check capacitors using your actual appliances at the intended environment and operating conditions.

### 7. Vibration and Shock

- 1. Please confirm the kind of vibration and/or shock, its condition, and any generation of resonance.
- Please mount the capacitor so as not to generate resonance, and do not allow any impact on the terminals.2. Mechanical shock due to being dropped may cause damage or a crack in the dielectric material of the capacitor. Do not use a dropped capacitor because the quality and reliability may be deteriorated.



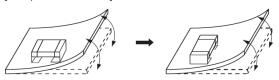
3. When printed circuit boards are piled up or handled, the corner of another printed circuit board should not be allowed to hit the capacitor, in order to avoid a crack or other damage to the capacitor.



## Soldering and Mounting

- 1. Mounting Position
- 1. Confirm the best mounting position and direction that minimizes the stress imposed on the capacitor during flexing or bending the printed circuit board.
- 1-1. Choose a mounting position that minimizes the stress imposed on the chip during flexing or bending of the board.

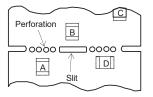
#### [Component Direction]



Locate chip horizontal to the direction in which stress acts.

[Chip Mounting Close to Board Separation Point]

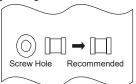
It is effective to implement the following measures, to reduce stress in separating the board. It is best to implement all of the following three measures; however, implement as many measures as possible to reduce stress.



Contents of Measures	Stress Level
<ol> <li>Turn the mounting direction of the component parallel to the board separation surface.</li> </ol>	A>D
(2) Add slits in the board separation part.	A>B
(3) Keep the mounting position of the component away from the board separation surface.	A>C

### [Mounting Capacitors Near Screw Holes]

When a capacitor is mounted near a screw hole, it may be affected by the board deflection that occurs during the tightening of the screw. Mount the capacitor in a position as far away from the screw holes as possible.

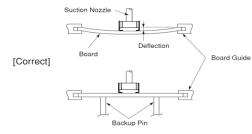


#### 2. Information before Mounting

- 1. Do not re-use capacitors that were removed from the equipment.
- 2. Confirm capacitance characteristics under actual applied voltage.
- 3. Confirm the mechanical stress under actual process and equipment use.
- 4. Confirm the rated capacitance, rated voltage and other electrical characteristics before assembly.
- 5. Prior to use, confirm the solderability of capacitors that were in long-term storage.
- 6. Prior to measuring capacitance, carry out a heat treatment for capacitors that were in long-term storage.
- 7. The use of Sn-Zn based solder will deteriorate the reliability of the MLCC.
- Please contact our sales representative or product engineers on the use of Sn-Zn based solder in advance.

#### 3. Maintenance of the Mounting (pick and place) Machine

- 1. Make sure that the following excessive forces are not applied to the capacitors.
- 1-1. In mounting the capacitors on the printed circuit board, any bending force against them shall be kept to a minimum to prevent them from any bending damage or cracking. Please take into account the following precautions and recommendations for use in your process.
  - (1) Adjust the lowest position of the pickup nozzle so as not to bend the printed circuit board.
  - (2) Adjust the nozzle pressure within a static load of 1N to 3N during mounting.
    - [Incorrect]



2. Dirt particles and dust accumulated between the suction nozzle and the cylinder inner wall prevent the nozzle from moving moving smoothly. This imposes greater force upon the chip during mounting, causing cracked chips. Also, the locating claw, when worn out, imposes uneven forces on the chip when positioning, causing cracked chips. The suction nozzle and the locating claw must be maintained, checked, and replaced periodically.

## 4-1. Reflow Soldering

- 1. When sudden heat is applied to the components, the mechanical strength of the components will decrease because a sudden temperature change causes deformation inside the components. In order to prevent mechanical damage to the components, preheating is required for both the components and the PCB. Preheating conditions are shown in table 1. It is required to keep the temperature differential between the solder and the components surface ( $\Delta$ T) as small as possible.
- Solderability of tin plating termination chips might be deteriorated when a low temperature soldering profile where the peak solder temperature is below the melting point of tin is used. Please confirm the solderability of tin plated termination chips before use.
- When components are immersed in solvent after mounting, be sure to maintain the temperature difference (ΔT) between the component and the solvent within the range shown in table 1.

Table 1

Part Number	Temperature Differential
KCA55	ΔT≦130°C

Standard Conditions

	Lead Free Solder
Peak Temperature	240 to 260°C
Atmosphere	Air or N2
and Free Colder On 2004 C	N.,

Lead Free Solder: Sn-3.0Ag-0.5Cu

#### 4. Optimum Solder Amount for Reflow Soldering

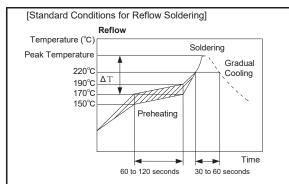
- 4-1. If solder paste is excessive, solder between a chip and a metal terminal melts. This causes the chip to move and come off.
- 4-2. If solder paste is too little, it causes a lack of adhesive strength on the metal terminal and the capacitor comes off.
- 4-3. Please make sure that solder is smoothly applied higher than 0.3mm and lower than the level of the bottom of the chip.

### Inverting the PCB

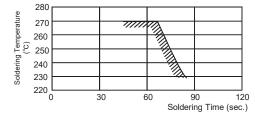
Make sure not to impose any abnormal mechanical shocks to the PCB.

#### 4-2. Flow Soldering

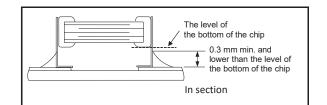
1. Do not apply flow soldering.



[Allowable Reflow Soldering Temperature and Time]

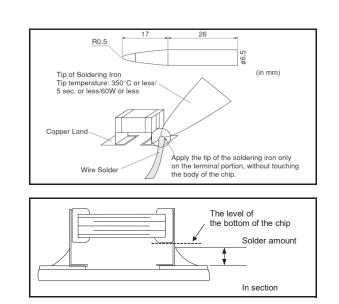


In the case of repeated soldering, the accumulated soldering time must be within the range shown above.



### 4-3. Correction of Soldered Portion

- 1. For the shape of the soldering iron tip, refer to the figure on the right.
- Regarding the type of solder, use a wire diameter of φ0.5mm or less (rosin core wire solder).
- 3. Apply the tip of the soldering iron against the lower end of the metal terminal.
  - In order to prevent cracking caused by sudden heating of the ceramic device, do not touch the ceramic base directly.
  - (2) In order to prevent deviations and dislocating of the chip, do not touch the junction of the chip and the metal terminal, and the metal portion on the outside directly.
- 4. The amount of solder for corrections by soldering iron, should be lower than the level of the bottom of the chip.

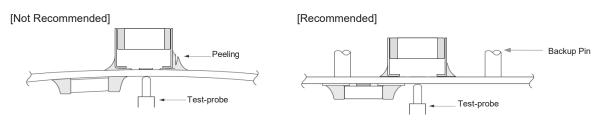


## 5. Washing

Excessive ultrasonic oscillation during cleaning can cause the PCBs to resonate, resulting in cracked chips or broken solder joints. Take note not to vibrate PCBs.

### 6. Electrical Test on Printed Circuit Board

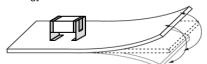
- 1. Confirm position of the backup pin or specific jig, when inspecting the electrical performance of a capacitor after mounting on the printed circuit board.
  - 1-1. Avoid bending the printed circuit board by the pressure of a test-probe, etc. The thrusting force of the test probe can flex the PCB, resulting in cracked chips or open solder joints. Provide backup pins on the back side of the PCB to prevent warping or flexing. Install backup pins as close to the capacitor as possible.
  - 1-2. Avoid vibration of the board by shock when a test-probe contacts a printed circuit board.

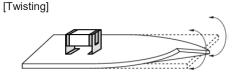


### 7. Printed Circuit Board Cropping

- 1. After mounting a capacitor on a printed circuit board, do not apply any stress to the capacitor that causes bending or twisting the board.
  - 1-1. In cropping the board, the stress as shown at right may cause the capacitor to crack. Cracked capacitors may cause deterioration of the insulation resistance, and result in a short. Avoid this type of stress to a capacitor.

[Bending]





2. Check the cropping method for the printed circuit board in advance.

2-1. Printed circuit board cropping shall be carried out by using a jig or an apparatus (Disk separator, router type separator,

c.) to prevent the mech	nanical stress that can occ	our to the board.		
Board Separation Method	Hand Separation	(1) Board Separation Jig	Board Sepa	ration Apparatus
Board Separation Method	Nipper Separation	(1) Board Separation Sig	(2) Disk Separator	(3) Router Type Separator
Level of stress on board	High	Medium	Medium	Low
Recommended	×	$\bigtriangleup^*$	$\triangle^*$	0
Notes	Hand and nipper separation apply a high level of stress. Use another method.	Board handling     Board bending direction     Layout of capacitors	<ul> <li>Board handling</li> <li>Layout of slits</li> <li>Design of V groove</li> <li>Arrangement of blades</li> </ul>	Board handling

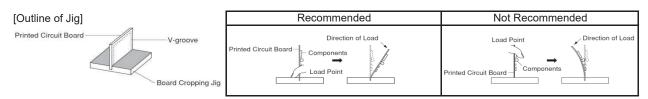
\* When a board separation jig or disk separator is used, if the following precautions are not observed,

a large board deflection stress will occur and the capacitors may crack. Use router type separator if at all possible.

## (1) Example of a suitable jig

[In the case of Single-side Mounting]

An outline of the board separation jig is shown as follows. Recommended example: Stress on the component mounting position can be minimized by holding the portion close to the jig, and bend in the direction towards the side where the capacitors are mounted. Not recommended example: The risk of cracks occurring in the capacitors increases due to large stress being applied to the component mounting position, if the portion away from the jig is held and bent in the direction opposite the side where the capacitors are mounted.



Controlling blade life

[In the case of Double-sided Mounting]

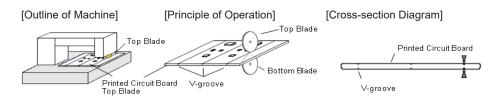
Since components are mounted on both sides of the board, the risk of cracks occurring can not be avoided with the above method. Therefore, implement the following measures to prevent stress from being applied to the components. (Measures)

- ① Consider introducing a router type separator. If it is difficult to introduce a router type separator, implement the following measures. (Refer to item 1. Mounting Position)
- ② Mount the components at a right angle to the board separation surface.
- 3 When mounting components near the board separation point, add slits in the separation position
- near the component.
- 4 Keep the mounting position of the components away from the board separation point.

#### (2) Example of a Disk Separator

An outline of a disk separator is shown as follows. As shown in the Principle of Operation, the top blade and bottom blade are aligned with the V-grooves on the printed circuit board to separate the board. In the following case, board deflection stress will be applied and cause cracks in the capacitors.

- ① When the adjustment of the top and bottom blades are misaligned, such as deviating in the top-bottom, left-right or front-rear directions
- ② The angle of the V groove is too low, depth of the V groove is too shallow, or the V groove is misaligned top-bottom IF V groove is too deep, it is possible to brake when you handle and carry it. Carefully design depth of the V groove with consideration about strength of material of the printed circuit board.



### Reference only

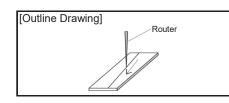
# A Caution

Recommended		Not Recommended					
Recommended	Top-bottom Misalignment	Left-right Misalignment	Front-rear Misalignment				
	te Top Blade	Top Blade	Top Blade				
Bottom Bla	de Bottom Blade	Bottom Blade	Bottom Blade				

Example of Recommended		Not Reco	ommended				
V-groove Design	Left-right Misalignment	Low-Angle	Depth too Shallow	Depth too Deep			

### (3) Example of Router Type Separator

The router type separator performs cutting by a router rotating at a high speed. Since the board does not bend in the cutting process, stress on the board can be suppressed during board separation. When attaching or removing boards to/from the router type separator, carefully handle the boards to prevent bending.



### 8. Assembly

#### 1. Handling

If a board mounted with capacitors is held with one hand, the board may bend. Firmly hold the edges of the board with both hands when handling. If a board mounted with capacitors is dropped, cracks may occur in the capacitors. Do not use dropped boards, as there is a possibility that the quality of the capacitors may be impaired.

- 2. Attachment of Other Components
- 2-1. Mounting of Other Components

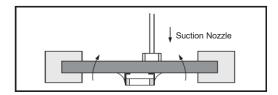
Pay attention to the following items, when mounting other components on the back side of the board after capacitors have been mounted on the opposite side. When the bottom dead point of the suction nozzle is set too low, board deflection stress may be applied to the capacitors on the back side (bottom side), and cracks may occur in the capacitors.

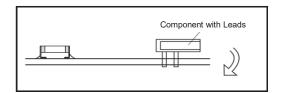
- After the board is straightened, set the bottom dead point of the nozzle on the upper surface of the board.
- · Periodically check and adjust the bottom dead point.

# 2-2. Inserting Components with Leads into Boards

When inserting components (transformers, IC, etc.) into boards, bending the board may cause cracks in the capacitors or cracks in the solder. Pay attention to the following.

- Increase the size of the holes to insert the leads, to reduce the stress on the board during insertion.
- Fix the board with backup pins or a dedicated jig before insertion.
- Support below the board so that the board does not bend.
   When using multiple backup pins on the board, periodically confirm that there is no difference in the height of each backup pin.





2-3. Attaching/Removing Sockets

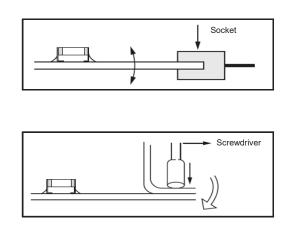
When the board itself is a connector, the board may bend when a socket is attached or removed. Plan the work so that the board does not bend when a socket is attached or removed.

2-4. Tightening Screws

The board may be bent, when tightening screws, etc. during the attachment of the board to a shield or chassis.

Pay attention to the following items before performing the work.

- · Plan the work to prevent the board from bending.
- Use a torque screwdriver, to prevent over-tightening of the screws.
- The board may bend after mounting by reflow soldering, etc. Please note, as stress may be applied to the chips by forcibly flattening the board when tightening the screws.



### Other

# 1. Under Operation of Equipment

- 1-1. Do not touch a capacitor directly with bare hands during operation in order to avoid the danger of an electric shock.
- 1-2. Do not allow the terminals of a capacitor to come in contact with any conductive objects (short-circuit). Do not expose a capacitor to a conductive liquid, including any acid or alkali solutions.
- 1-3. Confirm the environment in which the equipment will operate is under the specified conditions. Do not use the equipment under the following environments.
  - (1) Being spattered with water or oil.
  - (2) Being exposed to direct sunlight.
  - (3) Being exposed to ozone, ultraviolet rays, or radiation.
  - (4) Being exposed to toxic gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas, etc.)
  - (5) Any vibrations or mechanical shocks exceeding the specified limits.
  - (6) Moisture condensing environments.
- 1-4. Use damp proof countermeasures if using under any conditions that can cause condensation.

### 2. Other

- 2-1. In an Emergency
  - (1) If the equipment should generate smoke, fire, or smell, immediately turn off or unplug the equipment. If the equipment is not turned off or unplugged, the hazards may be worsened by supplying continuous power.
  - (2) In this type of situation, do not allow face and hands to come in contact with the capacitor or burns may be caused by the capacitor's high temperature.
- 2-2. Disposal of Waste

When capacitors are disposed of, they must be burned or buried by an industrial waste vendor with the appropriate licenses.

### 2-3. Circuit Design

(1) Addition of Fail Safe Function

Capacitors that are cracked by dropping or bending of the board may cause deterioration of the insulation resistance, and result in a short. If the circuit being used may cause an electrical shock, smoke or fire when a capacitor is shorted, be sure to install fail-safe functions, such as a fuse, to prevent secondary accidents.

(2) Capacitors used to prevent electromagnetic interference in the primary AC side circuit, or as a connection/insulation, must be a safety standard certified product, or satisfy the contents stipulated in the Electrical Appliance and Material Safety Law. Install a fuse for each line in case of a short.

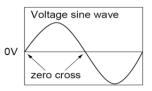
- 2-4. Test Condition for AC Withstanding Voltage
  - (1) Test Equipment

Test for AC withstanding voltage should be made with equipment capable of creating a wave similar to a 50/60 Hz sine wave.

(2) Voltage Applied Method

The capacitor's leads or terminals should be firmly connected to the output of the withstanding voltage test equipment, and then the voltage should be raised from near zero to the test voltage. If the test voltage is applied directly to the capacitor without raising it from near zero, it should be applied with the zero cross. \*At the end of the test time, the test voltage should be reduced to near zero, and then the capacitor's leads or terminals should be taken off the output of the withstanding voltage test equipment. If the test voltage is applied directly to the capacitor without raising it from near zero, surge voltage may occur and cause a defect.

\*ZERO CROSS is the point where voltage sine wave passes 0V. - See the figure at right -



### 2-5. Remarks

Failure to follow the cautions may result, worst case, in a short circuit and smoking when the product is used. The above notices are for standard applications and conditions. Contact us when the products are used in special mounting conditions. Select optimum conditions for operation as they determine the reliability of the product after assembly. The data herein are given in typical values, not guaranteed ratings.

#### 3. Limitation of applications

The products listed in the specification(hereinafter the product(s) is called as the "Product(s)") are designed and manufactured for applications specified in the specification. (hereinafter called as the "Specific Application")

We shall not warrant anything in connection with the Products including fitness, performance, adequateness, safety, or quality, in the case of applications listed in from (1) to (11) written at the end of this precautions, which may generally require high performance, function, quality, management of production or safety.

Therefore, the Product shall be applied in compliance with the specific application.

WE DISCLAIM ANY LOSS AND DAMAGES ARISING FROM OR IN CONNECTION WITH THE PRODUCTS INCLUDING BUT NOT LIMITED TO THE CASE SUCH LOSS AND DAMAGES CAUSED BY THE UNEXPECTED ACCIDENT, IN EVENT THAT (i) THE PRODUCT IS APPLIED FOR THE PURPOSE WHICH IS NOT SPECIFIED AS THE SPECIFIC APPLICATION FOR THE PRODUCT, AND/OR (ii) THE PRODUCT IS APPLIED FOR ANY FOLLOWING APPLICATION PURPOSES FROM (1) TO (11) (EXCEPT THAT SUCH APPLICATION PURPOSE IS UNAMBIGUOUSLY SPECIFIED AS SPECIFIC APPLICATION FOR THE PRODUCT IN OUR CATALOG SPECIFICATION FORMS, DATASHEETS, OR OTHER DOCUMENTS

- OFFICIALLY ISSUED BY US\*)
  - 1. Aircraft equipment
  - 2. Aerospace equipment
  - 3. Undersea equipment
  - 4. Power plant control equipment
  - 5. Medical equipment
  - 6. Transportation equipment
  - 7. Traffic control equipment
  - 8. Disaster prevention/security equipment
  - 9. Industrial data-processing equipment
  - 10. Combustion/explosion control equipment
  - 11. Equipment with complexity and/or required reliability equivalent to the applications listed in the above.

For exploring information of the Products which will be compatible with the particular purpose other than those specified in the specification, please contact our sales offices, distribution agents, or trading companies with which you make a deal, or via our web contact form.

Contact form: https://www.murata.com/contactform

\*We may design and manufacture particular Products for applications listed in (1) to (11). Provided that, in such case we shall unambiguously specify such Specific Application in the specification without any exception. Therefore, any other documents and/or performances, whether exist or non-exist, shall not be deemed as the evidence to imply that we accept the applications listed in (1) to (11).

# Notice

### Rating

### 1. Operating Temperature

- 1. The operating temperature limit depends on the capacitor.
  - 1-1. Do not apply temperatures exceeding the upper operating temperature. It is necessary to select a capacitor with a suitable rated temperature that will cover the operating temperature range. It is also necessary to consider the temperature distribution in equipment and the seasonal temperature variable factor.
  - 1-2. Consider the self-heating factor of the capacitor. The surface temperature of the capacitor shall be the upper operating temperature or less when including the self-heating factors.

### 2. Atmosphere Surroundings (gaseous and liquid)

1. Restriction on the operating environment of capacitors.

- 1-1. Capacitors, when used in the above, unsuitable, operating environments may deteriorate due to the corrosion of the terminations and the penetration of moisture into the capacitor.
- 1-2. The same phenomenon as the above may occur when the electrodes or terminals of the capacitor are subject to moisture condensation.
- 1-3. The deterioration of characteristics and insulation resistance due to the oxidization or corrosion of terminal electrodes may result in breakdown when the capacitor is exposed to corrosive or volatile gases or solvents for long periods of time.

### 3. Piezo-electric Phenomenon

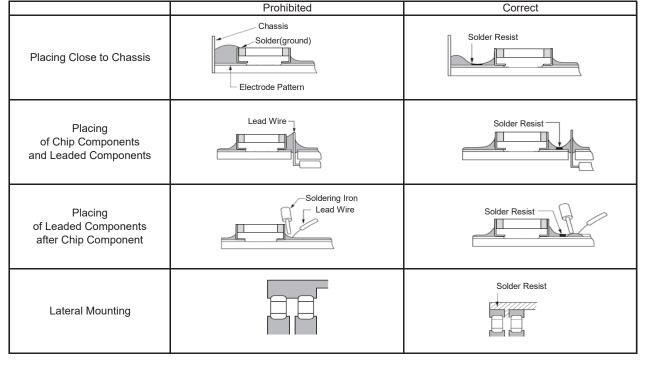
1. When using high dielectric constant type capacitors in AC or pulse circuits, the capacitor itself vibrates at specific frequencies and noise may be generated. Moreover, when the mechanical vibration or shock is added to the capacitor, noise may occur.

### Soldering and Mounting

## 1. PCB Design

- 1. Notice for Pattern Forms
  - 1-1. Unlike leaded components, chip components are susceptible to flexing stresses since they are mounted directly on the substrate. They are also more sensitive to mechanical and thermal stresses than leaded components. Excess solder fillet height can multiply these tresses and cause chip cracking. When designing substrates, take land patterns and dimensions into consideration to eliminate the possibility of excess solder fillet height.
  - 1-2. There is a possibility of chip cracking caused by PCB expansion/contraction with heat, because stress on a chip is different depending on PCB material and structure. When the thermal expansion coefficient greatly differs between the board used for mounting and the chip, it will cause cracking of the chip due to the thermal expansion and contraction.

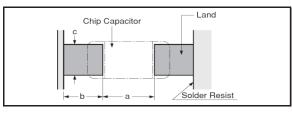
#### Pattern Forms



# Notice

## 2. Land Dimensions

2-1. Chip capacitors can be cracked due to the stress of PCB bending, etc. if the land area is larger than needed and has an excess amount of solder. Please refer to the land dimensions in the following table for reflow soldering. Please confirm the suitable land dimension by evaluating of the actual SET / PCB.

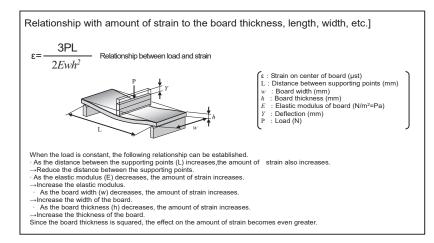


Unit:mm

Dimensions	Body size (L×W)	а	b	с
Part Number				
KCA5507UMF000L000	6.1×5.1	3.2 to 4.0	2.0 to 2.4	5.5 to 5.7

#### 3. Board Design

When designing the board, keep in mind that the amount of strain which occurs will increase depending on the size and material of the board.



#### 4. Washing

- 1. Please evaluate the capacitor using actual cleaning equipment and conditions to confirm the quality, and select the solvent for cleaning.
- 2. Unsuitable cleaning solvent may leave residual flux or other foreign substances, causing deterioration of electrical characteristics and the reliability of the capacitors.
- 3. Select the proper cleaning conditions.
- 3-1. Improper cleaning conditions (excessive or insufficient) may result in deterioration of the performance of the capacitors.

#### 5. Coating

- 1. A crack may be cause in the capacitor due to the stress of the thermal contraction of the resin during curing process. The stress is affected by the amount of resin and curing contraction. Select a resin with low curing contraction. The difference in the thermal expansion coefficient between a coating resin or a molding resin and the capacitor may cause the destruction and deterioration of the capacitor such as a crack or peeling, and lead to the deterioration of insulation resistance or dielectric breakdown. Select a resin for which the thermal expansion coefficient is as close to that of the capacitor as possible. A silicone resin can be used as an under-coating to buffer against the stress.
- Select a resin that is less hygroscopic. Using hygroscopic resins under high humidity conditions may cause the deterioration of the insulation resistance of a capacitor. An epoxy resin can be used as a less hygroscopic resin.

# Notice

## Other

### 1. Transportation

- 1. The performance of a capacitor may be affected by the conditions during transportation.
  - 1-1. The capacitors shall be protected against excessive temperature, humidity, and mechanical force during transportation.
    - Mechanical condition
      - Transportation shall be done in such a way that the boxes are not deformed and forced are not directly passed on to the inner packaging.
  - 1-2. Do not apply excessive vibration, shock, or pressure to the capacitor.
    - (1) When excessive mechanical shock or pressure is applied to a capacitor, chipping or cracking may occur in the ceramic body of the capacitor.
    - (2) When the sharp edge of an air driver, a soldering iron, tweezers, a chassis, etc. impacts strongly on the surface of the capacitor, the capacitor may crack and short-circuit.
  - 1-3. Do not use a capacitor to which excessive shock was applied by dropping, etc. A capacitor dropped accidentally during processing may be damaged.

### 2. Characteristics Evaluation in the Actual System

- 1. Evaluate the capacitor in the actual system, to confirm that there is no problem with the performance and specification values in a finished product before using.
- 2. Since a voltage dependency and temperature dependency exists in the capacitance of high dielectric type ceramic capacitors, the capacitance may change depending on the operating conditions in the actual system. Therefore, be sure to evaluate the various characteristics, such as the leakage current and noise absorptivity, which will affect the capacitance value of the capacitor.
- 3. In addition, voltages exceeding the predetermined surge may be applied to the capacitor by the inductance in the actual system. Evaluate the surge resistance in the actual system as required.

## \land Note

- 1. Please make sure that your product has been evaluated in view of your specifications with our product being mounted to your product.
- 2. You are requested not to use our product deviating from this specification.

# 1. Application

This product specification is applied to Safety Standard Certified Resin Molding SMD Type Multilayer Ceramic Capacitors Type MF.

The safety standard certification is obtained as Class X1, Y2.

## 1. Specific applications:

•Automotive powertrain/safety equipment: Products that can be used for automotive equipment related to running, turning, stopping, safety devices, etc., or equipment whose structure, equipment, and performance are legally required to meet technical standards for safety assurance or environmental protection.

• Consumer equipment: Products that can be used in consumer equipment such as home appliances, audio/visual equipment, communication equipment, information equipment, office equipment, and household robotics, and whose functions are not directly related to the protection of human life and property.

• Industrial equipment: Products that can be used in industrial equipment such as base stations, manufacturing equipment, industrial robotics equipment, and measurement equipment, and whose functions do not directly relate to the protection of human life and property.

•Medial Equipment [GHTF A/B/C] except for Implant Equipment: Products suitable for use in medical devices designated under the GHTF international classifications as Class A or Class B (the functions of which are not directly involved in protection of human life or property) or in medical devices other than implants designated under the GHTF international classifications as Class C (the malfunctioning of which is considered to pose a comparatively high risk to the human body).

• Automotive infotainment/comfort equipment: Products that can be used for automotive equipment such as car navigation systems and car audio systems that do not directly relate to human life and whose structure, equipment, and performance are not specifically required by law to meet technical standards for safety assurance or environmental protection.

2. Unsuitable Application: Applications listed in "Limitation of applications" in this product specification.

Approval standard and certified number

	Standard number	*Certified number	AC Rated voltage V(r.m.s.)	DC Rated voltage V
UL/cUL	UL60384-14, CSA E60384-14	E37921	250	1000
ENEC(VDE)	EN 60384-14	40039447	250	-

\*Above Certified number may be changed on account of the revision of standards and the renewal of certification.

## 2. Rating

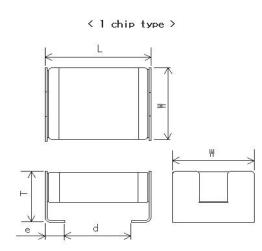
2-1. Operating temperature range Char. U2J : -55 to 125 °C

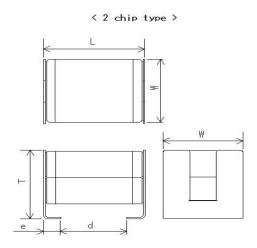
### 2-3. Part name configuration

ex.)	_							
KCA	55	W	7U	MF	103	М	L01	К
Series	Chip	Dimension	Temperature	Certified	Capacitance	Capacitance	Individual	Package
	Dimension	(T)	Characteristics	Туре		Tolerance	Specificatior	ı
	(L×W)							

Code 55		sion (mm)	
	L	W	
	5.7	5.0	
<ul> <li>Dimension (T)</li> </ul>			
Please refer to [Pa	art number list] on the dimer	nsions of metal tern	ninal product.
Code	Dimensio		
L	2.8		
Q	3.7	,	
W	6.4		
P	-3		
•Temperature Charac	teristics		
	tailed specification on [Spec	cification and test m	nethods].
Code	Temperature Cl	naracteristics	— , ,
70	U2J (E		
	(	/	H
<ul> <li>Certified Type</li> </ul>			
	y certified type name Type	MF	
	y contined type name Type		
Consiliants			
<ul> <li>Capacitance</li> </ul>			
	denote significant figures ;	the last digit denote	es the multiplier of 10 in
ex.) In case of 1	03 .		
10 ×	10 <sup>3</sup> = 10000 pF		
Canaditanaa Talarar			
Capacitance Tolerar			
Please refer to [Pa	irt number listj.		
<ul> <li>Individual Specificati</li> </ul>			
Murata's control co	ode		
Please refer to [Page 1]	art number list].		
•Package			
Code	Packa	age	
K	Φ330 mm reel		
	Φ180 mm reel		1
L			

# 3. Part number list





# Unit : mm

	Mussie Dari Number	то	0	Cap.		Dime	ension (	(mm)		Chip	Pack
Customer Part Number	Murata Part Number	T.C.	Cap.	tol. (%)	L	W	т	е	d	type	qty. (pcs)
	KCA55L7UMF101KL01K	U2J	100 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF151KL01K	U2J	150 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF221KL01K	U2J	220 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF331KL01K	U2J	330 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF471KL01K	U2J	470 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF681KL01K	U2J	680 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF102KL01K	U2J	1000 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF152KL01K	U2J	1500 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF222KL01K	U2J	2200 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55L7UMF332KL01K	U2J	3300 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	2000
	KCA55Q7UMF472KL01K	U2J	4700 pF	±10	6.1 ±0.4	5.1 ±0.3	3.7 ±0.2	0.9 ±0.2	4.0 min.	1	1000
	KCA55W7UMF103ML01K	U2J	10000 pF	±20	6.1 ±0.4	5.1 ±0.3	6.4 ±0.3	0.9 ±0.2	4.0 min.	2	500

	< 1 chip type >					< 2 L	chip ty	/pe > ≊	₩		
Customer Part Number	Murata Part Number	T.C.	Cap.	Cap. tol. (%)			ension (			nit : m Chip type	Pack qty. (pcs)
	KCA55L7UMF101KL01L	U2J	100 pF	(70) ±10	L 6.1 ±0.4	W 5.1 ±0.3	T 2.8 ±0.2	e 0.9 ±0.2	d 4.0 min.	1	400
	KCA55L7UMF151KL01L	U2J	150 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55L7UMF221KL01L	U2J	220 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55L7UMF331KL01L	U2J	330 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55L7UMF471KL01L	U2J	470 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55L7UMF681KL01L	U2J	680 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55L7UMF102KL01L	U2J	1000 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55L7UMF152KL01L	U2J	1500 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55L7UMF222KL01L	U2J	2200 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55L7UMF332KL01L	U2J	3300 pF	±10	6.1 ±0.4	5.1 ±0.3	2.8 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55Q7UMF472KL01L	U2J	4700 pF	±10	6.1 ±0.4	5.1 ±0.3	3.7 ±0.2	0.9 ±0.2	4.0 min.	1	400
	KCA55W7UMF103ML01L	U2J	10000 pF	±20	6.1 ±0.4	5.1 ±0.3	6.4 ±0.3	0.9 ±0.2	4.0 min.	2	200

Spe	cification							
No.	Test Ite	em	Specification	Test Method (		lard:AEC-Q200, , IEC60384 (all p	Ref. Standard:JI parts))	S C 5101(a
1	Pre-and Post-Stress Ele	ectrical Test		-				
2	High Temperature Expo	sure (Storage)	The measured and observed characteristics should satisfy the specifications in the following table.	Set the capacitor Let sit for 24±2 h			asure.	
		Appearance	No marking defects	-				
		Capacitance	Within ±5.0 % or ±0.5 pF	-				
		Change	(Whichever is larger.)					
		Q	Q ≧ 1,000	-				
		I.R.	More than 1,000 MΩ or 50 MΩ · μF					
			(Whichever is smaller.)					
3	Temperature Cycle		The measured and observed characteristics should satisfy the specifications in the following table.	conditions as (20	).		e manner and und	
		Appearance	No marking defects	following table.	o cycles accord	ng to the lour ne	eat treatments list	lea in the
		Capacitance	Within ±5.0 % or ±0.5 pF	Let sit for 24±2 h	at *room condit	ion, then measu	re.	
		Change	(Whichever is larger.)	r				
		Q	Q ≧ 1,000	Step	1	2	3	4
		I.R.	More than 1,000 MΩ or 50 MΩ · μF	Temp.	-55+0/-3	Room	125+3/-0	Room
			(Whichever is smaller.)	(°C) Time		Temp.		Temp
		Dielectric Strength		(min.)	15±3	1	15±3	1
	Destructive Physical An	alysis	No defects or abnormalities	Per EIA-469				
5	Moisture Resistance		The measured and observed characteristics should satisfy the specifications in the following table.	Apply the 24 h h below, 10 conse Let sit for 24±2 h	cutive times.		0 to 98 %) treatm re.	nent shown
		Appearance	No marking defects					
		Capacitance	Within ±6.0 % or ±0.6 pF					
		Change	(Whichever is larger.)	°C	Humidit 90-98%		midity Humidity	Humidity 90-98%
		Q	Q ≧ 350	70 65			4	
		I.R.	More than 1,000 MΩ or 50 MΩ · μF	65				
				45 40 40 25 30 15 10 5 -5 -10	Initial measurer	One cycle = 24	14 15 16 17 18 19 20	21222324
-1	Humidity Loading(AC)		The measured and observed characteristics should satisfy the specifications in the following table.	Apply the AC250 humidity.	V(r.m.s.) for 1,	000±12 h at 85	±3 °C in 80 to 85	% relative
		Appearance	No marking defects	Remove and let				
		Capacitance	Within ±6.0 % or ±0.6 pF	The charge/discl	arge current IS I	ess man 50 mA		
		Change	(Whichever is larger.)	1				
		Q	$Q \ge 200$	-				
		l.R.		-				
		LIX.	More than 100 M $\Omega$ or 5 M $\Omega \cdot \mu$ F	1				
2	Biased Humidity	I	(Whichever is smaller.) The measured and observed characteristics should	Apply the rated v	oltage (DC1000	V) and DC1 3+(	) 2-0 V (add 100	k0 resistor
-	(Humidity Loading (DC))		satisfy the specifications in the following table.	85±3 °C and 80 Remove and let	to 85 % humidity sit for 24±2 h at	for 1,000±12 h. *room condition,	then measure.	
		Appearance	No marking defects	The charge/discl	harge current is l	ess than 50 mA		
		Capacitance	Within ±6.0 % or ±0.6 pF	1				
		Change	(Whichever is larger.)	4				
		Q	Q ≧ 200	_				
		I.R.	More than 100 MΩ or 5 MΩ · μF (Whichever is smaller.)					
"roon	n condition" Temperatu	re : 15 to 35 °C, Rel	(Whichever is smaller.) ative humidity : 45 to 75 %, Atmosphere pressure : 86	to 106 kPa				

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and observed characteristics shoul cifications in the following table. fects or ±0.6 pF larger.) MΩ or 5 MΩ·μF smaller.) and observed characteristics shoul cifications in the following table.	Each individual capacitor should be subjected to a 5 kV impulses for three time or more. Then the capacitors are applied to life test. Then the capacitors are applied to life test. Time to half-value (T2) = 50 µs $0 \frac{(\%)}{1 + 1}$ The capacitors are placed in a circulating air oven for a period of 1,000 h. The air in the oven is maintained at maximum operating temperature +2/-0 °C, and relative humidity of 50 % max The charge/discharge current is less than 50 mA. Throughout the test, the capacitors are subjected to a AC425 V(r.m.s.) (170 % ac rated voltage) <50/60 Hz> alternating voltage of mains frequency, except th once each hour the voltage is increased to AC1000 V(r.m.s.) for 0.1 s.
or ±0.6 pF larger.) MΩ or 5 MΩ·μF smaller.) and observed characteristics shoul cifications in the following table. fects	Front time (T1) = 1.7 µs=1.67T Time to half-value (T2) = 50 µs The capacitors are placed in a circulating air oven for a period of 1,000 h. The air in the oven is maintained at maximum operating temperature +2/-0 °C, and relative humidity of 50 % max The charge/discharge current is less than 50 mA. Throughout the test, the capacitors are subjected to a AC425 V(r.m.s.) (170 % ac rated voltage) <50/60 Hz> alternating voltage of mains frequency, except the once each hour the voltage is increased to AC1000 V(r.m.s.) for 0.1 s. Impulse voltage Each individual capacitor should be subjected to a 5 kV impulses for three time
or ±0.6 pF larger.) MΩ or 5 MΩ·μF smaller.) and observed characteristics shoul cifications in the following table. fects	<b>90</b> <b>1</b> Time to half-value (12) = 50 µs <b>50</b> <b>30</b> <b>1</b> Time to half-value (12) = 50 µs <b>50</b> <b>30</b> <b>1</b> Time to half-value (12) = 50 µs The capacitors are placed in a circulating air oven for a period of 1,000 h. The air in the oven is maintained at maximum operating temperature +2/-0 °C, and relative humidity of 50 % max The charge/discharge current is less than 50 mA. Throughout the test, the capacitors are subjected to a AC425 V(r.m.s.) (170 % ac rated voltage) <50/60 Hz> alternating voltage of mains frequency, except th once each hour the voltage is increased to AC1000 V(r.m.s.) for 0.1 s.           Id         Impulse voltage           Each individual capacitor should be subjected to a 5 kV impulses for three time
larger.) MΩ or 5 MΩ·μF smaller.) and observed characteristics shoul cifications in the following table. fects	The capacitors are placed in a circulating air oven for a period of 1,000 h. The air in the oven is maintained at maximum operating temperature +2/-0 °C, and relative humidity of 50 % max The charge/discharge current is less than 50 mA. Throughout the test, the capacitors are subjected to a AC425 V(r.m.s.) (170 % ac rated voltage) <50/60 Hz> alternating voltage of mains frequency, except the once each hour the voltage is increased to AC1000 V(r.m.s.) for 0.1 s. Id Impulse voltage Each individual capacitor should be subjected to a 5 kV impulses for three time
and observed characteristics shoul cifications in the following table.	The capacitors are placed in a circulating air oven for a period of 1,000 h. The air in the oven is maintained at maximum operating temperature +2/-0 °C, and relative humidity of 50 % max The charge/discharge current is less than 50 mA. Throughout the test, the capacitors are subjected to a AC425 V(r.m.s.) (170 % ac rated voltage) <50/60 Hz> alternating voltage of mains frequency, except the once each hour the voltage is increased to AC1000 V(r.m.s.) for 0.1 s. Id Impulse voltage Each individual capacitor should be subjected to a 5 kV impulses for three time
and observed characteristics shoul cifications in the following table.	The capacitors are placed in a circulating air oven for a period of 1,000 h. The air in the oven is maintained at maximum operating temperature +2/-0 °C, and relative humidity of 50 % max The charge/discharge current is less than 50 mA. Throughout the test, the capacitors are subjected to a AC425 V(r.m.s.) (170 % ac rated voltage) <50/60 Hz> alternating voltage of mains frequency, except the once each hour the voltage is increased to AC1000 V(r.m.s.) for 0.1 s. Id Impulse voltage Each individual capacitor should be subjected to a 5 kV impulses for three time
and observed characteristics shoul cifications in the following table.	T2         The capacitors are placed in a circulating air oven for a period of 1,000 h.         The air in the oven is maintained at maximum operating temperature +2/-0 °C, and relative humidity of 50 % max         The charge/discharge current is less than 50 mA.         Throughout the test, the capacitors are subjected to a AC425 V(r.m.s.) (170 % ac rated voltage) <50/60 Hz> alternating voltage of mains frequency, except th once each hour the voltage is increased to AC1000 V(r.m.s.) for 0.1 s.         Id       Impulse voltage Each individual capacitor should be subjected to a 5 kV impulses for three time
and observed characteristics shoul cifications in the following table. fects	Impulse voltage         Each individual capacitor should be subjected to a 5 kV impulses for three time
cifications in the following table.	The air in the oven is maintained at maximum operating temperature +2/-0 °C, and relative humidity of 50 % max         The charge/discharge current is less than 50 mA.         Throughout the test, the capacitors are subjected to a AC425 V(r.m.s.) (170 % ac rated voltage) <50/60 Hz> alternating voltage of mains frequency, except th once each hour the voltage is increased to AC1000 V(r.m.s.) for 0.1 s.         Id       Impulse voltage         Each individual capacitor should be subjected to a 5 kV impulses for three time
cifications in the following table.	Each individual capacitor should be subjected to a 5 kV impulses for three time
or ±0.6 pF	<b>100</b> $\frac{(\%)}{100}$ Front time (T1) = 1.7 µs=1.67T Time to helf value (T2) = 50 µs
larger.)	<b>90</b> Time to half-value (T2) = 50 μs
	30-
M $\Omega$ or 5 M $\Omega$ ·µF	
smaller.)	
	Remove and let sit for 24±2 h at *room condition, then measure. The charge/discharge current is less than 50 mA.
abnormalities	Visual inspection
	Using calipers and micrometers.
gible.	The capacitor should be inspected by naked eyes.
fects	Per MIL-STD-202 Method 215 Solvent 1 : 1 part (by volume) of isopropyl alcohol 3 parts (by volume)
cified tolerance.	of mineral spirits
	Solvent 2 : Terpene defluxer Solvent 3 : 42 parts (by volume) of water 1part (by volume) of propylene
	glycol monomethyl ether 1 part (by volume) of monoethanolomine
fects	Three shocks in each direction should be applied along 3 mutually perpendicula
cified tolerance.	axes of the test specimen (18 shocks).
	The specified test pulse should be half sine and should have a duration : 0.5 m peak value : 1,500 g and velocity change : 4.7 m/s.
abnormalities	Solder the capacitor to the test jig (glass epoxy board) in the same manner and
	under the same conditions as (20).
	The capacitor should be subjected to a simple harmonic motion having a total
	amplitude of 1.5 mm, the frequency being varied uniformly between the approximate limits of 10 and 2,000 Hz. The frequency range, from 10 to 2,000 and return to 10 Hz, should be traversed in approximately 20 min. This motion should be applied for 12 items in each 3 mutually perpendicular directions (total of 36 times).
	abnormalities cified dimensions egible. effects cified tolerance. 00 MΩ or 50 MΩ · μF smaller.) effects cified tolerance. abnormalities cified tolerance.

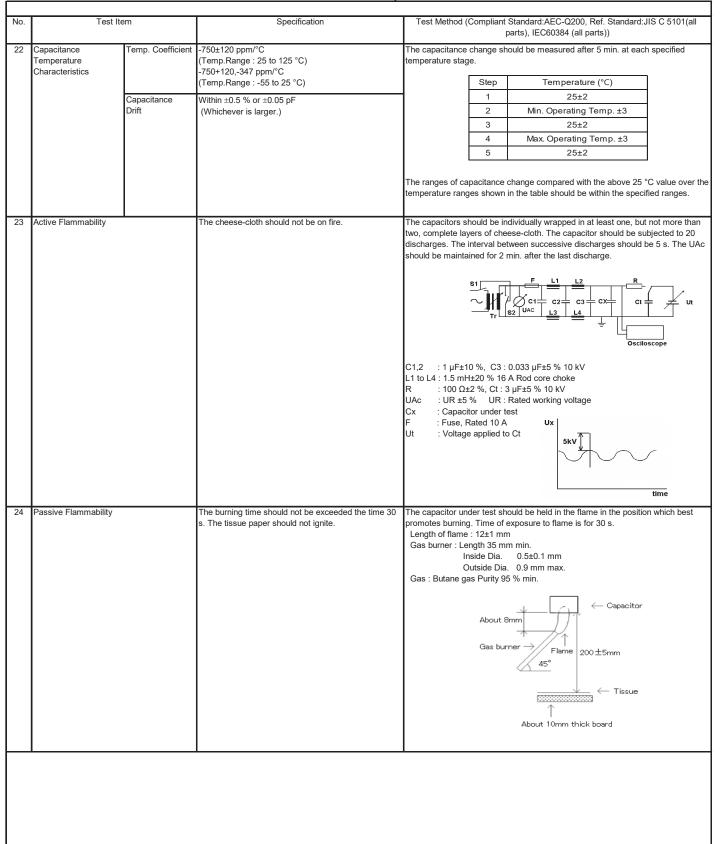
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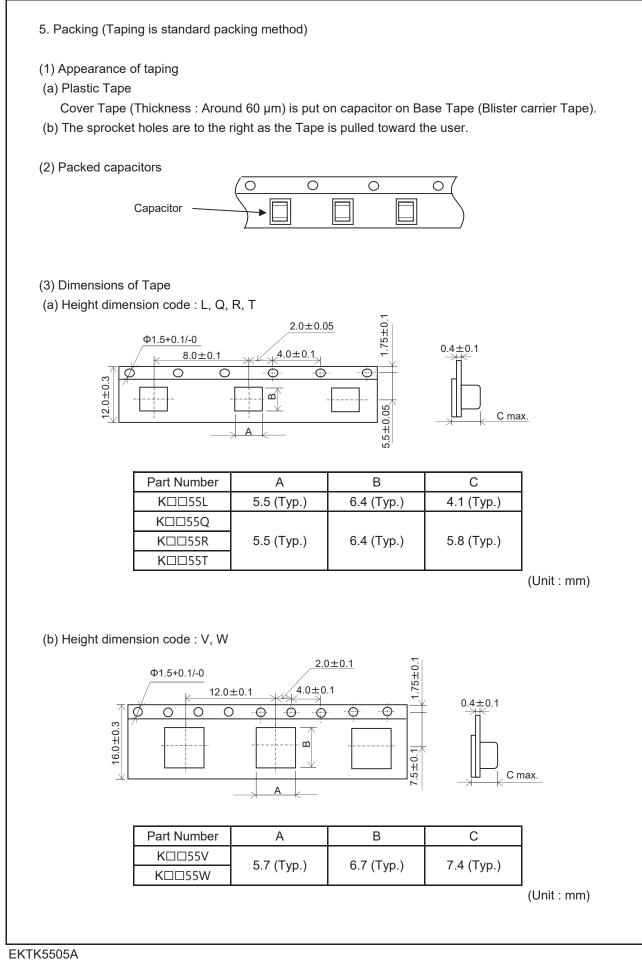
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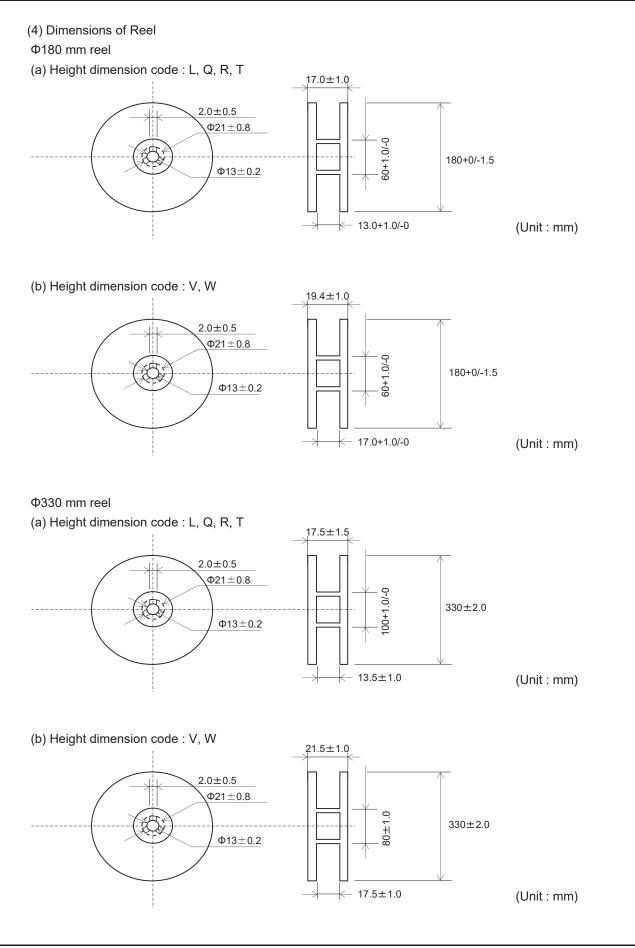
No.	Test Ite	em	Specification	Test Method (Compliant Standard:AEC-Q200, Ref. Standard:JIS C 5101(all parts), IEC60384 (all parts))
14	Resistance to Soldering	Heat	The measured and observed characteristics should satisfy the specifications in the following table.	Reflow Soldering : Peak 260+0/-5 °C The area of soldering 230 °C min., 20 to 40 s Let sit for 24±2 h at room condition*, then measure.
		Appearance	No marking defects	
		Capacitance	Within the specified tolerance.	
		Q	Q ≧ 1,000	300 °C
		I.R.	More than 1,000 MΩ or 50 MΩ · μF	230 % 40 % 230 °C min.
			(Whichever is smaller.)	200 °C
		Dielectric Strength	Per Item 18	180 °C
				150 °C
				100 °C
				60 to 120 s
15	Thermal Shock		The measured and cheering characteristics should	Figure approximation to the supporting its in the same meaning and under the same
15	Thermal Shock		The measured and observed characteristics should satisfy the specifications in the following table.	Fix the capacitor to the supporting jig in the same manner and under the same conditions as (20). Perform the 300 cycles according to the two heat treatments
				listed in the following table (Maximum transfer time is 20 s.).
		Appearance	No marking defects	Let sit for 24±2 h at *room condition, then measure.
		Capacitance Change	Within ±5.0 % or ±0.5 pF	Step 1 2
		Ű	(Whichever is larger.)	Temp. (°C) -55+0/-3 125+3/-0
		Q I.R.	$Q \ge 1,000$	(°C) 5010/0 12010/0
		1.17.	More than 1,000 MΩ or 50 MΩ · μF (Whichever is smaller.)	(min.) 15±3 15±3
16	ESD	Appearance	No marking defects	Per AEC-Q200-002
		Capacitance	Within the specified tolerance.	
		Q.	Q ≧ 1,000	4
		I.R.	More than 1,000 MΩ or  50 MΩ · μF	
			(Whichever is smaller.)	
17	Solderability	•	95 % of the terminations are to be soldered evenly and	
			continuously.	After the preheating, following test is done. Reflow Soldering : Peak 260+0/-5 °C
				The area of soldering 230 °C min., 20 to 40 s
				Let sit for 24±2 h at room condition*, then measure.
				300 °C ── 260+0/-5 °C
				20 to 40 s 230 °C min.
				200 °C —
				180 °C
				150 °C
				60 to 120 s
				<ul> <li>b) Should be placed into steam aging for 8 h±15 min.</li> <li>After the preheating, following test is done.</li> </ul>
				Reflow Soldering : Peak 260+0/-5 °C
				The area of soldering 230 °C min., 20 to 40 s Let sit for 24±2 h at room condition*, then measure.
				Lot on for LTTE in at room contaition , then measure.
				300 °C
				20 to 40 s
				230 °C min.
				200 °C
				180 °C
				100 °C
				60 to 120 s
* "roor	n condition" Temperatu	re : 15 to 35 °C, Rel	I lative humidity : 45 to 75 %, Atmosphere pressure : 86 t	to 106 kPa

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No	Test It		Creation	Test Method (Compliant Standard AEC 0200, Def. Standard: US 0 5101/all
No.	Test It		Specification	Test Method (Compliant Standard:AEC-Q200, Ref. Standard:JIS C 5101(all parts), IEC60384 (all parts))
18	Electrical Characterization	Appearance	No defects or abnormalities	Visual inspection.
	Characterization	Capacitance	Within the specified tolerance	The capacitance/Q should be measured at 25 °C at the frequency and voltage
		Q	Q≧1,000	shown in the table.
				Nominal Measuring Measuring
				capacitance         frequency         volgate           C<1000 pF
				$C \ge 1000 \text{ pF} \qquad 1\pm 0.2 \text{ kHz}$
		I.R. 25 °C	More than 10,000 MΩ or 100 MΩ · μF	The insulation resistance should be measured with DC500±50 V at 25 °C and 125
		1.0.405.00	(Whichever is smaller.)	°C within 2 min. of charging.
		I.R. 125 °C	More than 1,000 MΩ or 10 MΩ · μF	
		Distantia	(Whichever is smaller.)	
		Dielectric Strength	No failure	No failure should be observed when voltage in the table is applied between the terminations for 60±1 s., provided the charge/discharge current is less than 50
		g		mA.
				Test Voltage
				AC2000 V(r.m.s.)
				DC3000 V
10	Poord Flow	Appearance	No marking defeate	Colder the consister on the test is (glass analy beard) shown in Fig1 using
19	Board Flex	Appearance	No marking defects	Solder the capacitor on the test jig (glass epoxy board) shown in Fig1 using solder. Then apply a force in the direction shown in Fig 2 for 60 s. The soldering
		Capacitance Change	Within ±10.0 % or ±1.0 pF (Whichever is larger.)	should be done by the reflow method and should be conducted with care so that
		Shange		the soldering is uniform and free of defects such as heat shock.
				Type a b c
				KCA55 4.5 8.0 5.6 (in mm)
				(mm)
				$  \frac{b}{4.5} $ $\phi 4.5$ <b>20</b> 50 Procesurizing
				speed:1.0mm/s
			<u> </u>	
				100 Capacitance meter
				100 Capacitance meter
				Fig 1
				rig. t : 1.6mm Fig.2
20	Terminal Strength	A	No marking defects	Solder the capacitor to the test jig (glass epoxy board) shown in Fig.3 using
20	reminal Suengui	Appearance		conder the suparities to the test jig (glass sport bound) shown in Fig.s doing
20	Terminal Strength			solder. Then apply 18 N force in parallel with the test jig for 60 s.
20	Terminal Strength	Appearance Capacitance Q	Within specified tolerance	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with
20		Capacitance Q	Within specified tolerance $Q \ge 1,000$	solder. Then apply 18 N force in parallel with the test jig for 60 s.
20	renninai Suengui	Capacitance	Within specified tolerance	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
20	reminal Suengui	Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
20	reminal Suengui	Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
20	reminal Suengui	Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type         a         b         c           KCA55         4.0         8.0         5.6
20	reminal Suengui	Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type         a         b         c           KCA55         4.0         8.0         5.6
20	reminal Strength	Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type         a         b         c           KCA55         4.0         8.0         5.6
20		Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c KCA55 4.0 8.0 5.6 (in mm) C C C C C C C C C C C C C
20		Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c KCA55 4.0 8.0 5.6 (in mm) C C C C C C C C C C C C
20		Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c KCA55 4.0 8.0 5.6 (in mm) C KCA55 KA
20		Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c KCA55 4.0 8.0 5.6 (in mm) (in mm) (it : 1.6 mm)
20		Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c KCA55 4.0 8.0 5.6 (in mm) (in mm) (in mm) Fig. 3 Solder resist
20		Capacitance Q	Within specified tolerance $Q \ge 1,000$ More than 1,000 M $\Omega$ or 50 M $\Omega$ ·µF	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c KCA55 4.0 8.0 5.6 (in mm) (in mm) (it : 1.6 mm)
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c KCA55 4.0 8.0 5.6 (in mm) (in mm) Fig.3 Solder resist Baked electrode or copper foil
20	Beam Load Test	Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock. Type a b c KCA55 4.0 8.0 5.6 (in mm) (in mm) (in mm) Fig.3 Solder resist Baked electrode or copper foil
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.
		Capacitance Q	Within specified tolerance         Q ≥ 1,000         More than 1,000 MΩ or 50 MΩ • μF         (Whichever is smaller)	solder. Then apply 18 N force in parallel with the test jig for 60 s. The soldering should be done by the reflow method and should be conducted with care so that the soldering is uniform and free of defects such as heat shock.







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_ K⊂	nt section : 16	$\frac{50 \text{ min.}}{\Rightarrow}$	Capacitors	s mounting un	it Vacan	t section : 190	min. 米	210 min.	——————————————————————————————————————
0	<u> </u>				0			5	
	> c	Direction of fe	eed					(Uni	t : mm)
(6) The to	on tane or c	over tane	and base	tano aro n	ot attache	d at the end	of the tar	e for a m	inimum of
5 pitch									
(7) Missin contini		rs number	within 0.	1 % of the	number pe	r reel or 1 po	c, whiche	ver is grea	ater, and not
	op tape or c I not cover			om tape sho	ould not pr	otrude beyo	nd the ed	ges of the	e tape and
(9) Cumu	lative tolera	ance of sp	rocket ho	les, 10 pitc	hes : ±0.3	mm.			
	ing off form		G N in th	a direction	ahown on	the fellowe			
(10) Peeli	ing off force	e : 0.1 to 0	0.6 N in th	e direction	shown on	the follows.			
(10) Peeli	ing off force		0.6 N in th	e direction		the follows.	Гаре		
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